

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KIMURA ET AL.	
		Examiner Allen T. Cao	Art Unit 2652	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,905,255 A	05-1999	Wakabayashi et al.	250/201.5
*	B	US-6,343,053 B1	01-2002	Akanuma et al.	369/44.14
*	C	US-5,208,703 A	05-1993	Ikegame et al.	359/813
*	D	US-6,639,744 B2	10-2003	Ohno, Takehide	359/824
*	E	US-6,532,118 B2	03-2003	Ohno, Takehide	359/824
*	F	US-5,627,687	05-1997	Fujisawa, Hirotoshi	359/823
*	G	US-2002/0071189 A1	06-2002	Ohno, Takehide	359/813
*	H	US-6,181,670 B1	01-2001	Nagasato, Makoto	720/681
*	I	US-6,625,105 B2	09-2003	Suzuki et al.	720/681
*	J	US-5,220,459 A	06-1993	Ichikawa et al.	359/811
*	K	US-2003/0184886 A1	10-2003	Wakabayashi et al.	359/819
*	L	US-5,663,840	09-1997	Matsui, Tsutomu	359/814
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP401192022A	08-1989	Japan	Hirotoshi et al	-----
	O	Derwent 2003-437295	02-2003	China	Choi et al	-----
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.